# MOSFET – Power, Single N-Channel 60 V, 15 mΩ, 37 A

#### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK4 Package, Industry Standard
- AEC-Q101 Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

#### **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	60	V
Gate-to-Source Voltage	9		$V_{GS}$	±20	V
Continuous Drain	Steady State	T <sub>C</sub> = 25°C	I <sub>D</sub>	36	Α
Current R <sub>0JC</sub> (Notes 1, 2, 3)	State	T <sub>C</sub> = 100°C		21	
Power Dissipation		T <sub>C</sub> = 25°C	$P_{D}$	37	W
R <sub>θJC</sub> (Notes 1, 2)		T <sub>C</sub> = 100°C		12	
Continuous Drain Current R <sub>0JA</sub>	Steady State	T <sub>A</sub> = 25°C	I <sub>D</sub>	12	Α
(Notes 1, 2, 3)	State	T <sub>A</sub> = 100°C		8.4	
Power Dissipation		T <sub>A</sub> = 25°C	$P_{D}$	3.8	W
R <sub>θJA</sub> (Notes 1 & 2)		T <sub>A</sub> = 100°C		1.9	
Pulsed Drain Current	$T_A = 25$	°C, t <sub>p</sub> = 10 μs	I <sub>DM</sub>	185	Α
Operating Junction and Storage Temperature			T <sub>J</sub> , T <sub>stg</sub>	–55 to + 175	°C
Source Current (Body Diode)			I <sub>S</sub>	31	Α
Single Pulse Drain-to-Source Avalanche Energy (T <sub>J</sub> = 25°C, I <sub>L(pk)</sub> = 1.6 A)			E <sub>AS</sub>	65	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)			TL	260	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

#### THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	4.1	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

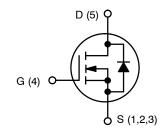
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- 3. Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



#### ON Semiconductor®

#### www.onsemi.com

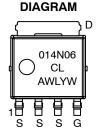
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
60 V	15 mΩ @ 10 V	07.4
	21.5 m $\Omega$ @ 4.5 V	37 A



**N-CHANNEL MOSFET** 



LFPAK4 CASE 760AB



**MARKING** 

014N06CL = Specific Device Code A = Assembly Location

WL = Wafer Lot
 Y = Year
 W = Work Week

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 5 of this data sheet.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise specified)

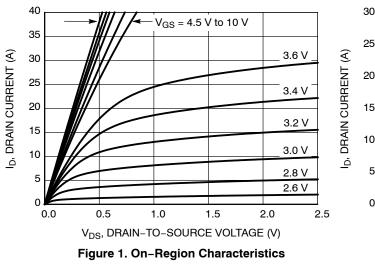
Parameter	Symbol	Test Condition		Min	Тур	Max	Unit
OFF CHARACTERISTICS							•
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	V <sub>GS</sub> = 0 V, I <sub>D</sub> =	250 μΑ	60			V
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> / T <sub>J</sub>				26		mV/°C
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$ ,	T <sub>J</sub> = 25 °C			10	μΑ
		$V_{DS} = 60 \text{ V}$	T <sub>J</sub> = 125°C			250	1
Gate-to-Source Leakage Current	I <sub>GSS</sub>	V <sub>DS</sub> = 0 V, V <sub>GS</sub> = 20 V				100	nA
ON CHARACTERISTICS (Note 4)						•	•
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 25 μΑ	1.2		2.0	V
Negative Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.0		mV/°C
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 10 V	I <sub>D</sub> = 10 A		12.5	15	mΩ
		V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 10 A		17.9	21.5	1
Forward Transconductance	9FS	V <sub>DS</sub> = 15 V, I <sub>D</sub>	= 15 A		43		S
CHARGES, CAPACITANCES & GATE RESIS	TANCE					•	•
Input Capacitance	C <sub>ISS</sub>	V <sub>GS</sub> = 0 V, f = 1 MHz, V <sub>DS</sub> = 25 V			620		pF
Output Capacitance	Coss				340		1
Reverse Transfer Capacitance	C <sub>RSS</sub>				7.0		1
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			4.5		nC
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			9.7		1
Threshold Gate Charge	Q <sub>G(TH)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub> = 48 V; I <sub>D</sub> = 10 A			1.3		
Gate-to-Source Charge	$Q_{GS}$				2.1		
Gate-to-Drain Charge	$Q_{GD}$				1.0		1
Plateau Voltage	$V_{GP}$				3.1		V
SWITCHING CHARACTERISTICS (Note 5)					-		
Turn-On Delay Time	t <sub>d(ON)</sub>	V <sub>GS</sub> = 10 V, V <sub>DS</sub>	<sub>S</sub> = 48 V,		7.0		ns
Rise Time	t <sub>r</sub>	$I_D = 10 \text{ A}, R_G = 10 \text{ A}$	= 1.0 Ω		13		1
Turn-Off Delay Time	t <sub>d(OFF)</sub>				25		1
Fall Time	t <sub>f</sub>				6.0		1
DRAIN-SOURCE DIODE CHARACTERISTIC	s				-		
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	T <sub>J</sub> = 25°C		0.85	1.2	V
		$I_S = 10 \text{ A}$ $T_J = 125^\circ$			0.72		1
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, dIS/dt} = 20 \text{ A/}\mu\text{s,}$ $I_{S} = 10 \text{ A}$			23.8		ns
Charge Time	t <sub>a</sub>				11.9		1
Discharge Time	t <sub>b</sub>				11.8		1
Reverse Recovery Charge	Q <sub>RR</sub>				11.6		nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.

5. Switching characteristics are independent of operating junction temperatures.

#### **TYPICAL CHARACTERISTICS**



25 V<sub>DS</sub> = 10 V

20 V<sub>DS</sub> = 10 V

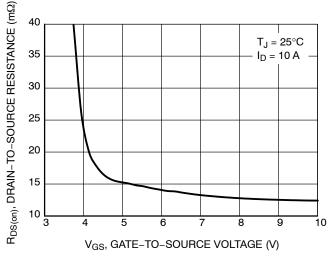
10 T<sub>J</sub> = 25°C

T<sub>J</sub> = 125°C

T<sub>J</sub> = -55°C

V<sub>GS</sub>, GATE-TO-SOURCE VOLTAGE (V)

Figure 2. Transfer Characteristics



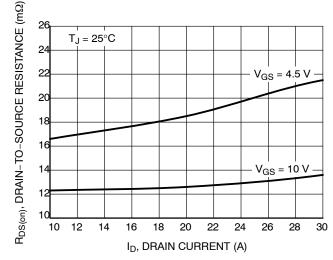
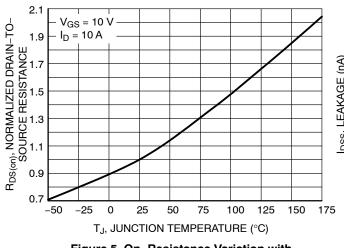


Figure 3. On-Resistance vs. Gate-to-Source Voltage

Figure 4. On-Resistance vs. Drain Current and Gate Voltage



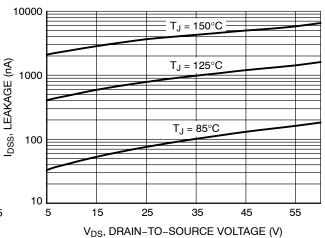


Figure 5. On–Resistance Variation with Temperature

Figure 6. Drain-to-Source Leakage Current vs. Voltage

#### **TYPICAL CHARACTERISTICS**

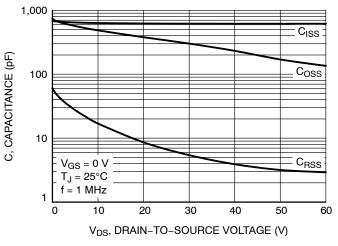


Figure 7. Capacitance Variation

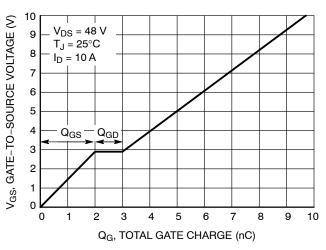


Figure 8. Gate-to-Source vs. Total Charge

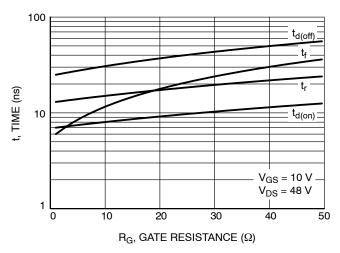


Figure 9. Resistive Switching Time Variation vs. Gate Resistance

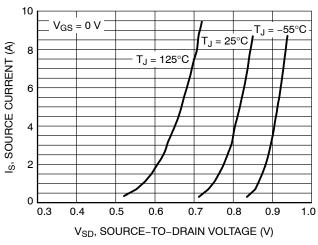


Figure 10. Diode Forward Voltage vs. Current

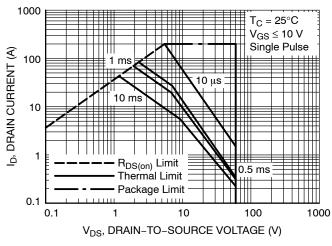


Figure 11. Maximum Rated Forward Biased Safe Operating Area

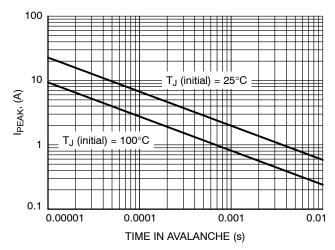


Figure 12. I<sub>PEAK</sub> vs. Time in Avalanche

#### **TYPICAL CHARACTERISTICS**

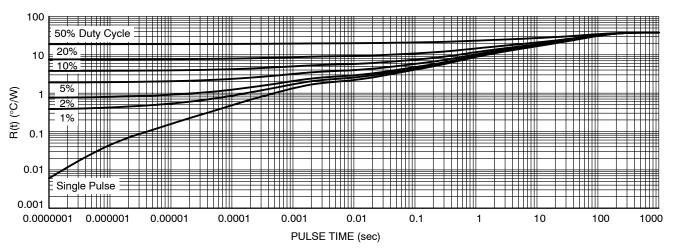
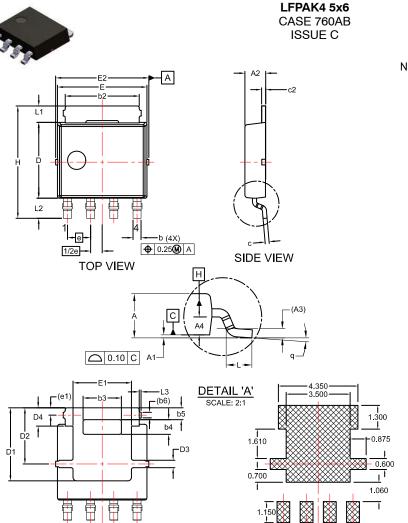


Figure 13. Thermal Characteristics

#### **DEVICE ORDERING INFORMATION**

Device	Marking	Package	Shipping <sup>†</sup>
NVMYS014N06CLTWG	014N06CL	LFPAK4 (Pb-Free)	3000 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.



DATE 19 NOV 2019

#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: MILLIMETERS.
- 3. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- 4. DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- 5. DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

UNIT IN MILLIMETER				
DIM	MIN	NOM	MAX	
Α	1.10	1.20	1.30	
A1	0.00	0.08	0.15	
A2	1.10	1.15	1.20	
А3	(	).25 REF		
A4	0.45	0.50	0.55	
b	0.40	0.45	0.50	
b2	3.80	4.10	4.40	
b3	2.00	2.10	2.20	
b4	0.70	0.80	0.90	
b5	0.55	0.65	0.75	
b6		0.31 REI	F	
С	0.19	0.22	0.25	
c2	0.19	0.22	0.25	
D	4.05	4.15	4.25	
D1	3.80	4.00	4.20	
D2	3.00	3.10	3.20	
D3	0.30	0.40	0.50	
D4	0.90	1.00	1.10	
Е	4.80	4.90	5.00	
E1	3.10	3.20	3.30	
E2	5.00	5.15	5.30	
е		1.27 BS0		
1/2e		0.635 BS		
e1	0,40 REF			
Η	6.00	6.15	6.30	
L	0.40	0.65	0.85	
L1	0.80	0.90	1.00	
L2	0.90	1.10	1.30	
L3	0.00	0.10	0.20	
q	0°	4°	8°	

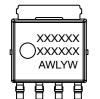
#### DETAILS, PLEASE DOWNLO

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRIMD.

RECOMMENDED LAND PATTERN

## GENERIC MARKING DIAGRAM\*

**BOTTOM VIEW** 



XXXXXX = Specific Device Code A = Assembly Location

WL = Wafer Lot

Y = Year W = Work Week

\*This information is generic. Please refer to device data sheet for actual part marking. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:	98AON82777G	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	LFPAK4 5x6		PAGE 1 OF 1	

ON Semiconductor and are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

onsemi, ONSEMI., and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at <a href="www.onsemi.com/site/pdf/Patent-Marking.pdf">www.onsemi.com/site/pdf/Patent-Marking.pdf</a>. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does onsemi assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems. or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

#### ADDITIONAL INFORMATION

TECHNICAL PUBLICATIONS:

 $\textbf{Technical Library:} \ \underline{www.onsemi.com/design/resources/technical-documentation}$ 

onsemi Website: www.onsemi.com

ONLINE SUPPORT: www.onsemi.com/support

For additional information, please contact your local Sales Representative at

www.onsemi.com/support/sales